

Beamline EPS Acceptance Testing

Doc No. BL-EPS-002 Rev: B

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Rev Date:

09/16/2015 Barrett Clay

Author: Approved:

09/16/2015

<u>Title</u>

<u>Name</u>

Approval Date

Controls Infrastructure Group Leader ES&H Operations Manager Quality Assurance Engineer Ruslan Kadyrov Lori Stiegler Joseph Zipper

09/16/2015 09/16/2015 09/16/2015

Seria	al No	Part No	Part Rev	ECN	Rev	ECN	Rev
Beamline: 11-BM CMS						8	
eviati	ion & Waive	r:		-			
OP	Description	n		Name/Life #)ate	DR
	Follow the E	S&H and Personal Protective Equipment ts for the area.		R Kadyrov #25392	1	27/16	- DIX
20	contains a va	uring and test equipment used for this proced alid calibration label in accordance with NSL Procedure PS-QAP-0901, where applicable.		R Kadyrov # 25392	07,	127/16	
	supervisor ar discrepancie procedure. A	an is responsible for notifying the technical nd/or the cognizant engineer of any s occurring during the performance of this Il discrepancies shall be identified and reporte with NSLS-II Discrepancy Reporting Process					
30		NFORMATION - This step shall be performe t EPS Engineer.	ed by	R Kadgion 25392	081	105/16	
	A) Record the box for "Pa	e relevant Beamline name on this sheet, in t art No".	he	-7,72			
	·	is entire traveler and write in the relevant oftware, and procedure numbers where req	uired				
		ON VERIFICATION		R. Kadgrov	107	1/29/16	
	Drawing No.:	levant drawing(s): 21 (kb) EL-BL-ET-EPS-340-95 Rev. No.: A Rev. No.:		¥ 2539 <u>2</u>		1-2110	
	B) Verify the	following items are acceptable:					
	System L	ayout configured per drawing(s) abeled / Tagged					



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OP	Description	Name/Life #	Date	DR
50	SOFTWARE CONFIGURATION	Pladyrov 25392	07/29/16	
	A) Download PLC software to controller and verify it was accepted by the controller.	25392	6.27 m A0.42	
	B) Record the software part number: LT-EL-BL- ET-EPS - 21/0 - 70 Part No.: Rev. No.:			
60	ACCEPTANCE TESTING	R kadyrov 25392	08/05/16	
	A) List relevant testing procedure	25392	00/0 ///	
	Procedure No.: PS-R-XFD-EPS Rev. No.: 1			
	B) Verify acceptable completion of test procedure			
	C) Attach test report to this traveler			
65	WATER LEAK DETECTION SYSTEM TEST	R. Kadyrov 25332	08/05/16	
	Verify water leak detection system, as designed for this beamline, functions correctly.	25392	31 416	
70	Verify All Traveler Operations Complete	25352	08/05/16	
80	REVISION HISTORY (This step is informational and does not			
	require signoff)			
	Rev - Description - Date A First Release 8/27/2014 B OP#65 added 9/16/15 Joe Delong removed as approver Ruslan Kadyrov added as approver			

Brookhaven National Laboratory/ Photon Sciences Directorate									
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Beam Line: 11 BM CMS

Test Date:

EPS Engineer: Ruslan Kadyrov

BL Group Leader: Masafumi Fukuto

Beam Line master spreadsheet:

https://ps.bnl.gov/phot/BeamlineSupportDocs/CMS/Controls/LT-R-XFD-CO-DR-CMS-001_Rev2.xlsx

Pre-test setup:

Connect PPS interface test box at beam line EPS/PPS interface connector.

The Beam Line Master Spreadsheet contains a comprehensive list of all EPS related signals. As this test plan is executed note the results in the "test results" column of this spreadsheet.

Test Set 1: Vacuum

Vacuum Section:

Starting conditions: pressure at or below acceptable limits, GVs open.

Simulate pressure rise (toward poor vacuum) by disabling the vacuum gauge controller channel. Ensure EPICS PVs enter proper alarm states, photon shutter closes¹ and vacuum section is isolated. Two local gate valves and one (or more, if it is required to isolate upstream section, e.g. section branching) upstream gate valve close. Record results for the following:

EPICS PV Alarm

EPS fault

Photon Shutter closes

GVx closes

GVy close:

GVz closes

Attempt to open the front end shutter and gate valves through EPICS.

Photon shutter and gate valves cannot be opened through EPICS (1)

¹ if the intensity of the beam in the section cannot cause damage to its valves, poor vacuum doesn't have to cause shutter close

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Enable vacuum gauge controller and ensure EPICS alarms clear. Open gate valves and photon shutter through EPICS.

Photon shutter and gate valves can be opened through EPICS (2)

		(1)	(2)			
Gauge name:	Shutter:	d/s GV:	u/s GV:	D u/s:		
XF:11BMA-VA{Mono:DMM-CCG:1}	FE SH	V	V	hla	V	V
XF:11BMA-VA{Mono:DMM-TCG:1}		-		ula	V	V
XF:11BMA-VA{Mir:Tor-CCG:1}	FE SH	V	V		V	V
XF:11BMA-VA{Mir:Tor-TCG:1}					V	V
XF:11BMA-VA{FS:2-CCG:1}	PE SH	V	V	_	V	V
XF:11BMA-VA{FS:2-TCG:1}			-		V	V
XF:11BMA-VA{BT-CCG:1}	FE SH	V	1		V	V
XF:11BMA-VA{BT-TCG:1}					V	~
XF:11BMB-VA{Mir:KB-TCG:1}		_))
XF:11BMB-VA{Chm:Det-TCG:1}	_	_	_			
XF:11BMB-VA{BS:SAXS-TCG:1}					_	

Simulate pressure rise (toward poor vacuum) by disabling the vacuum pump controller channel. Ensure EPICS PVs enter proper alarm states, photon shutter closes² and vacuum section is isolated. Two local gate valves and one upstream (or more, if it is required to isolate upstream section, e.g. section branching) gate valve close. Record results for the following:

EPICS PV Alarm

EPS fault

Photon Shutter closes

GVx closes

GVy closes

GVz closes

Attempt to open the front end shutter and gate valves through EPICS.

Photon shutter and gate valves cannot be opened through EPICS (1)

Enable vacuum pump controller and ensure EPICS alarms clear. Open gate valves and photon shutter through EPICS.

² if the intensity of the beam in the section cannot cause damage to its valves, poor vacuum doesn't have to cause shutter close

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Photon shutter and gate valves can be opened through EPICS (2)

Repeat for each vacuum section on beam line. For the sections adjacent to Front end and End Station, also simulate poor vacuum signal from remote systems.

EPS fault:	Front end:	End station:
Photon Shutter closes	V	419
GVx closes GV2	V	419
GVy closes	410	4/6
GVz closes	4/0	4/9
Shutter and GVs cannot be opened	V	4/9

.3		(1)	(2)			
Gauge name:	Shutter:	d/s GV:	u/s GV:	D u/s:		
XF:11BMA-VA{BC:1-IP:1}	FE SH	appropriately.	V	4/4	V	V
XF:11BMA-VA{Mono:DMM-IP:1}	FESH	~	V		L	L
XF:11BMA-VA{Mir:Tor-IP:1}	PESU	V	V		~	V
XF:11BMA-VA{FS:2-IP:1}	FE SU	V	V		V	V
XF:11BMA-VA{BT-IP:1}	FE SU	-	V		V	V
XF:11BMA-VA{BT-IP:2}	FE SH	_	V		V	L
XF:11BMA-VA{BT-IP:3}	FE SU		V		V	V

Test Set 2: Water flow

Water flow Section:

Record initial flow through section with all valves fully open.

Slowly close supply valve and record the LOW and LOW LOW PV Alarm levels.

If the channel is associated with an EPS action (e.g. XFD-EPOS), also register the flow at which the EPS fault occurs. Ensure cable disconnection results in EPS action.

Repeat for each water circuit on beam line.

Sensor name:	Nominal flow:	LOW:	LOLO:	EPS:
XF:11BMA-OP{Mono:DMM}F-I	0,49 GPM	0.25	0,2	PE SH
XF:11BMB-ES{Det:WAXS}F-I	0.54GPM	0,4	0,3	FE SH

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Test Set 3: Thermal

For each temperature transducer ensure the temperature measurement reports expected value.

Attach an appropriate adaptor and transducer simulator to the temperature input of the EPS system (remote IO chassis or Armor Block). Raise the temperature above each of the HI and HIHI PV alarm limits and ensure the alarm is reported. If the transducer is associated with an EPS interlock, continue to raise the temperature until the EPS trip level is exceeded. Ensure the appropriate EPS mitigation process occurs. Ensure channel cable disconnection results in EPS action.

Us.	·C	ےہ	OC	-
Sensor name:	Temperature:	HI:	HIHI:	EPS:
XF:11BMA-OP{Msk:1}T-I	23.8	40,0	500	FE SH
XF:11BMA-OP{Mono:DMM}T:0-I	25.6	400	500	FE SU
XF:11BMA-OP{Mono:DMM}T:1-I	25,3	40.0	50,0	FE S4
XF:11BMA-OP{Mono:DMM}T:2-I	25.4	400	50.0	FE Sh
XF:11BMA-OP{BS:1}T-I	23.5	40,0	590	FE SH
XF:11BMA-OP{Mir:Tor}T:1-I	23,4	35.0	40.0	FE SU
XF:11BMA-OP{Mir:Tor}T:2-l	23.4	35.0	40,0	FE S4
XF:11BMA-OP{BS:2}T-I	23,6	35.0	40.0	FE SH
XF:11BM{RG:A1}T-I	23.1			_

FE JU - Front End Shutter "-" no EPS action, as expected

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Test Set 4: EPS/PPS interface

For the primary Photon Shutter:

Front End: If FRONT END ENABLE STATUS and FOE SECURE and not USER INTERLOCK command the front end shutter to open.

Front end opens and FRONT END OPEN STATUS = OPEN: V

Command the front end shutter to close.

Front end closes and FRONT END OPEN STATUS = CLOSED: V

With the front end open force a user interlock.

Attempt to open the front end shutter through EPICS while not all gate valves in white-beam region down to next secondary shutter are open.

Front end cannot be opened through EPICS: λ

For each secondary photon shutter:

If PHOTON SHUTTER x ENABLE STATUS = 1 (ABILITY TO OPEN) and ESEE x SECURE command the shutter to open.

Shutter opens and PHOTON SHUTTER x OPEN STATUS = OPEN $\sqrt{}$

Command the shutter to close.

Shutter closes and PHOTON SHUTTER x OPEN STATUS = CLOSED $\sqrt{}$

Attempt to open the shutter through EPICS while not all gate valves in white-beam region downstream the shutter are open.

Shutter cannot be opened through EPICS:

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Brookhaven National Laboratory/ Photon Sciences Directorate						
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Appendix A

Differential Vacuum Interlocks

Remove the analog output cable from the MKS vacuum gauge controller for the Pirani gauges of XF:11BMB-VA{Mir:KB-TCG:1} and XF:11BMB-VA{Mir:KB-TCG:1} signals. Inject with two "Dial-A-Volt" voltage simulators (e.g. DATEL DVC-350A) a voltage (nominal 2.95V) to simulate a vacuum level in each of these chambers that are within 0.1 millibar (0.075 torr) of the other but between 0.25 and 100 millibar of pressure. Record the nominal pressure level used for differential testing. **Pressure** $\frac{\partial_{t} 22}{\partial_{t} 2} \frac{\partial_{t} 22}{\partial_{t} 22} \frac{\partial_{t} 22}{\partial_{t} 2} \frac{\partial$

Open Gate Valve XF:11BMB-VA{Slt:4-GV:1}. Verify the front end shutter can be enabled. Raise slowly the analog voltage of one vacuum signal level until the gate valve trips closed. Record the pressure level that creates the trip. Verify that the Front End is disabled. Return analog signal level back to previous pressure level. Open the gate valve and verify that the Front End is again enabled. Raise slowly the analog voltage of the other vacuum signal level until the gate valve trips closed. Record the pressure level that causes a trip. Verify that the Front End is disabled. Return analog signal level back to previous pressure level. Open the gate valve and verify that the Front End is again enabled.

Vacuum	Trip Pressure	Gate valve closed	FE disabled
XF:11BMB-VA{Mir:KB-TCG:1}	0.42	V	
XF:11BMB-VA{Mir:KB-TCG:1}	0,42		

kaise the simulated pressure level to 125 mbar for bot	n gauge signals. Vary one signal by more than 2 millibar
and verify that a trip condition does not occur. No Trip	V
, ,	y

Open Gate Valve XF:11BMB-VA{Chm:Det-GV:1}. Verify the front end shutter can be enabled. Raise slowly the analog voltage of one vacuum signal level until the gate valve trips closed. Record the pressure level that creates the trip. Verify that the Front End is disabled. Return analog signal level back to previous pressure level. Open the gate valve and verify that the Front End is again enabled. Raise slowly the analog voltage of the other vacuum signal level until the gate valve trips closed. Record the pressure level that causes a trip. Verify that the Front End is disabled. Return analog signal level back to previous pressure level. Open the gate valve and verify that the Front End is again enabled.

Vacuum	Trip Pressure	Gate valve closed	FE disabled
XF:11BMB-VA{Chm:Det-TCG:1}	0,42	V	Keyrage Eg.
XF:11BMB-VA{BS:SAXS-TCG:1}	0.42	V	

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Raise the simulated pressure level to 125 mbar for both gauge signals. Vary one signal by more than 2 millibar and verify that a trip condition does not occur. **No Trip**

Appendix B

End Station Pump Logic

Set or confirm the nominal EPICS float derivative (dP/dT) trip variable for both End Station Pumps #1 and #2 to 100 mbar/sec.

Remove the analog signals from the Pfeifer PCR 260 Compact Pirani Capacitance Gauges used on the End Station sections #1 and #3 with the output signals from a two channel wave form signal generator (e.g. Tektronix AFG310). Set the #3 channel to a fixed DC value shown as the nominal voltage in the below tables. Set the function generator for a rising ramp wave form with peak-to-peak voltage amplitude of 0.5 (±0.25) volts. Apply a DC offset identical to the nominal voltage applied to the #3 channel. Set the frequency of the ramp function to a lower frequency than the anticipated Calc. Trip frequency. Attach the running signal generator signal to section #1. Turn ON End Station pump #1 and verify this pump does not trip OFF. Raise the frequency of the function generator until pump #1 trips OFF. Record the frequency of the ramp waveform. Repeat this test for all four nominal pressure levels, remembering to apply a new DC offset for both signals.

Test dP/dt #1

	42
_	

P (mbar)	Nominal V (DC)	Calc. Trip (HZ)	Held	Meas. Trip (HZ) f	dP/dt trip meas.
10	6.5	8.7	6.8	6.9	79.4
30	6.98	2.9	1.8	1,9	65,6
100	7.5	0.87	944	0.46	529
300	7.97	0.29	0,11	0,12	41,44

Swap the two signal cables from the signal generator so that the ramp waveform is now attached to channel #3. Turn ON End Station pump #1 and verify this pump does not trip OFF. Raise the frequency of the function generator until pump #1 trips OFF. Record the frequency of the ramp waveform. Repeat this test for all four nominal pressure levels, remembering to apply a new DC offset for both signals.

Test dP/dt #3

- 1.	,,
H	7

P (mbar)	Nominal V (DC)	Calc. Trip (HZ)	Held	Meas. Trip (HZ) f	dP/dt trip meas.
10	6.5	8.7	6.8	6.9	79.4
30	6.98	2.9	1.8	1,9	65,6
100	7.5	0.87	0,44	0,46	59
300	7.97	0.29	0.11	0.12	41,44

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Replace the analog signals from the Pfeifer PCR 260 Compact Pirani Capacitance Gauges used on the End Station sections #1 and #3.

Remove the analog signal from the Pfeifer PCR 260 Compact Pirani Capacitance Gauges used on the End Station sections #2. Apply the ramp waveform of the signal generator to the channel #2 input. Turn ON End Station pump #2 and verify this pump does not trip OFF. Raise the frequency of the function generator until pump #2 trips OFF. Record the frequency of the ramp waveform that caused this trip. Repeat this test for all four nominal pressure levels, remembering to apply a new DC offset.

Test dP/dt #2

1/2

P (mbar)	Nominal V (DC)	Calc. Trip (HZ)	Held	Meas. Trip (HZ) f	dP/dt trip meas.
10	6.5	8.7	6,8	6.9	79.4
30	6.98	2.9	1.8	1,9	65,6
100	7.5	0.87	0,44	0,46	53
300	7.97	0.29	0,11	0,12	41.44

To calculate the measured pressure derivative (dP/dt) the following formula is provided:

$$\frac{dP}{dt} = \frac{P * f}{2 * log_{10}(e)} \cong \frac{P * f}{0.8686}$$

Enter the calculated number in the provided column.